Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination SHIMIZU ET AL.	
Hae M. Hyeon	2839	

Hae M. Hyeon

SEARCHED					
Class	Subclass	Date	Examiner		
Search	Updated	12/05	hmh		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
439	660	12/05	hmh		
439	636	\frac{1}{\sqrt{2}}	\bigvee		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Interference Search Done	12/05	hmh		